



# RADIATED EMISSION

Model Name : DBS 200B03

Model No. :

Serial No. :

Temperature : 25deg C

Detector : PEAK/QP

Points : 4

Polarization : Hori. & Vert.

Limit1: [EN 55022] Class B<3m>

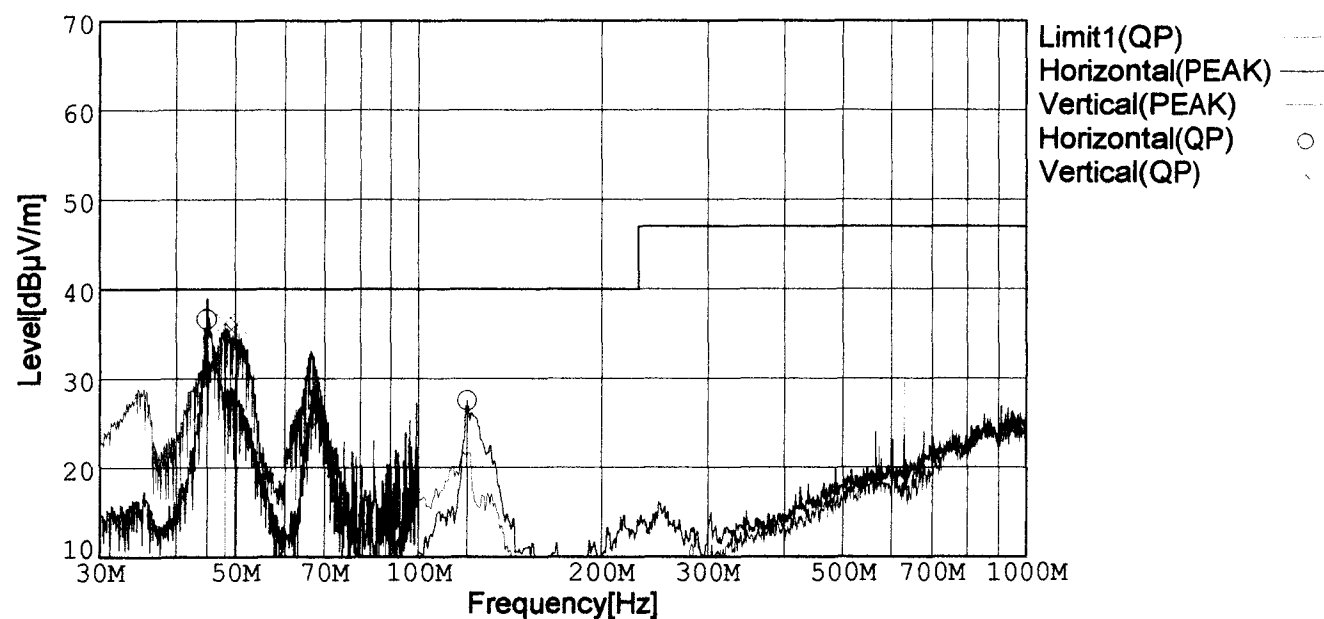
Humidity : 40%

Comment : AC230V Io=100%

Tested by : J.HATAGISHI

Date : 1999/4/9 18:40

EMI Receiver(s) : R3261A,ESPC



Frequency [MHz]	Meter Reading [dBμV]	Antenna Factor [dB]	Cable Loss [dB]	Level [dBμV/m]	Angle [°]	Height [cm]	Pola.	Limit [dBμV/m]	Margin [dB]
44.775	53.7	10.2	-27.3	36.6	283	146	Hori.	40.0	3.4
120.091	41.4	11.4	-25.3	27.5	328	131	Hori.	40.0	12.5
48.039	52.0	8.6	-24.4	36.2	106	110	Vert.	40.0	3.8
50.219	52.6	7.5	-24.0	36.1	94	101	Vert.	40.0	3.9

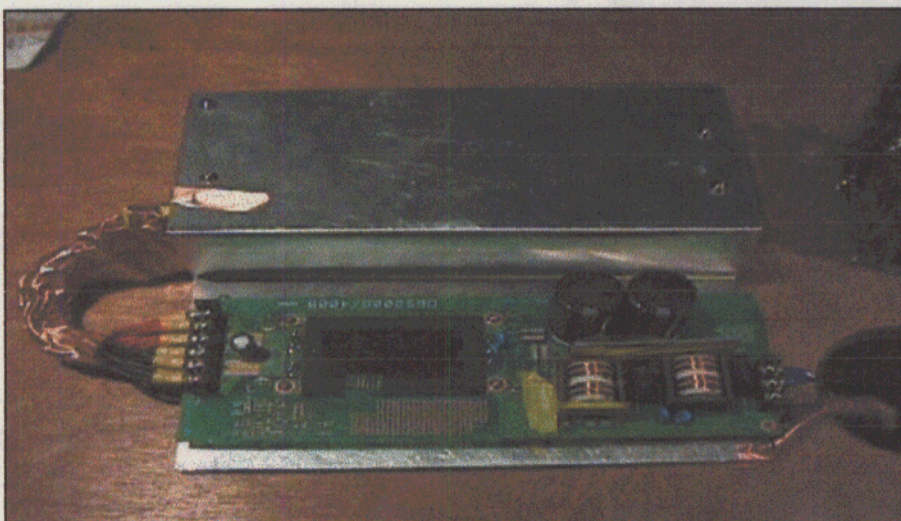
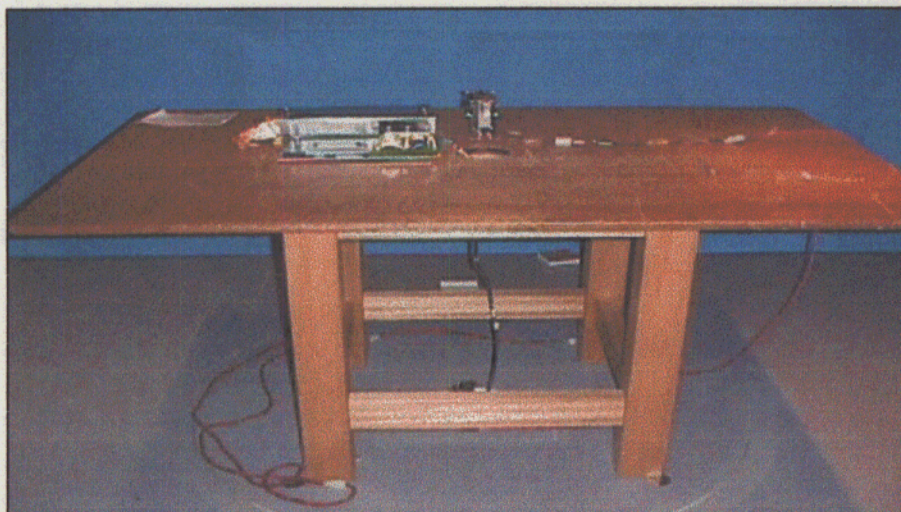


# Conditions

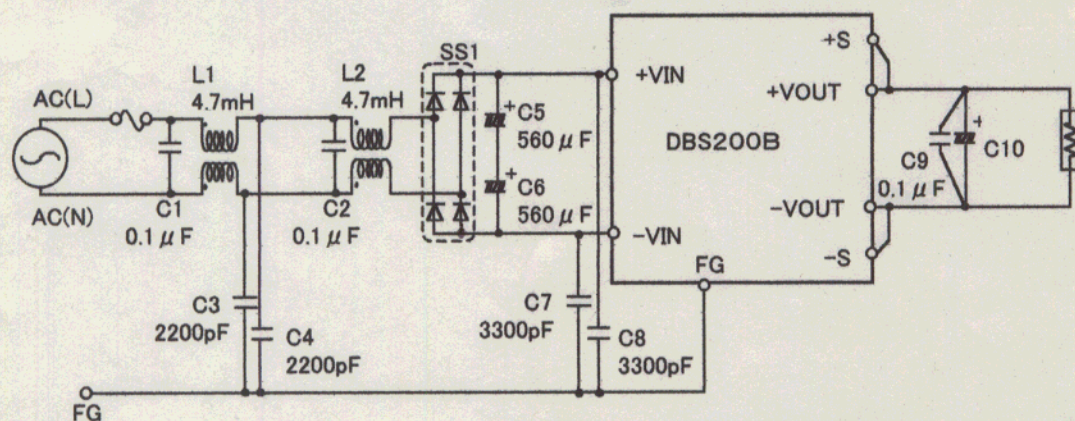
Date 1999/4/9

Test : RADIATED EMISSION  
Model Name : DBS200B

## Photographs of Test Set-Up



## Testing circuitry



- L1, L2 : SS35H-35047 (TOKIN)  
C5, C6 : 250V 560  $\mu$ F (NICHICON:GQseries)  
C10 : 10V 2200  $\mu$ F (DBS200B03,05,07)  
25V 1000  $\mu$ F (DBS200B12)  
SS1 : D10XB60 (SINDENG)

Fig. Testing circuitry





# LINE CONDUCTION

Model Name : DBS 200B03

Model No. :

Serial No. :

Temperature : 25deg C

Detector : PEAK/QP/Ave.

Points : 6

Line Mode : VA/VB

Limit1: [EN 55022] Class B(QP)

Limit2: [EN 55022] Class B(Ave.)

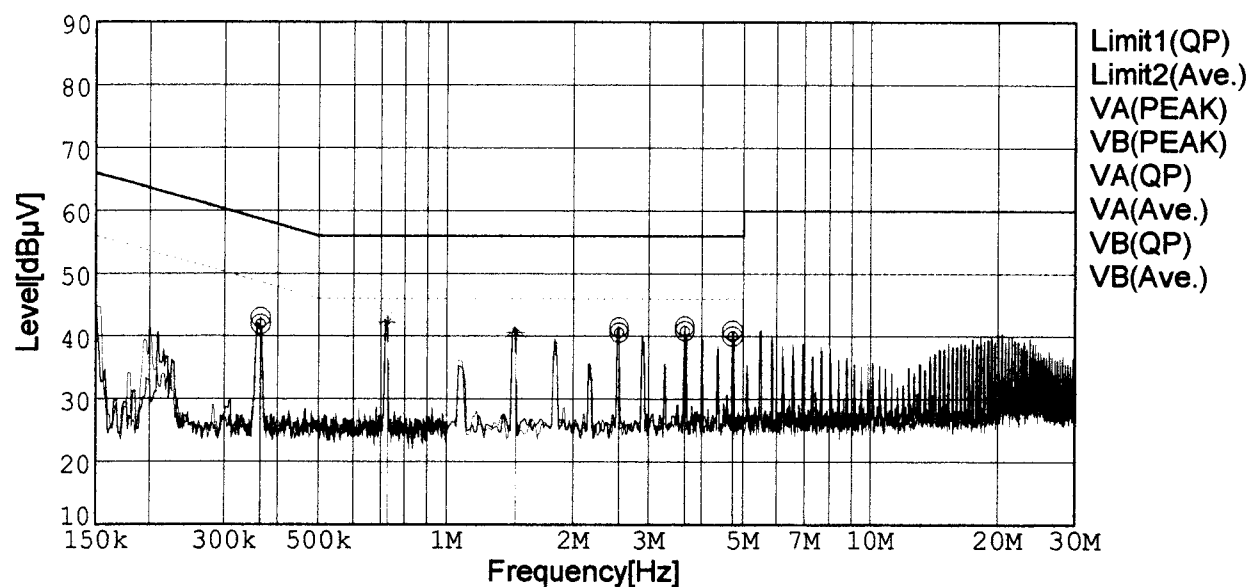
Humidity : 40%

Comment : AC230V Io=100%

Tested by : J.HATAGISHI

Date : 1999/4/9 18:11

EMI Receiver(s) : R3261A,ESPC



Frequency [MHz]	Meter Reading (QP) [dBμV]	Meter Reading (Ave.) [dBμV]	Factor [dB]	Level (QP) [dBμV]	Level (Ave.) [dBμV]	Line	Limit (QP) [dBμV]	Limit (Ave.) [dBμV]	Margin (QP)[dB]	Margin (Ave.) [dB]
0.3635	32.7	31.6	10.3	43.0	41.9	VA	58.6	48.6	15.6	6.7
2.5465	31.4	30.5	10.1	41.5	40.6	VA	56.0	46.0	14.5	5.4
3.6354	31.4	30.6	10.2	41.6	40.8	VA	56.0	46.0	14.4	5.2
4.7242	30.7	29.8	10.2	40.9	40.0	VA	56.0	46.0	15.1	6.0
0.7253	32.9	32.1	10.2	43.1	42.3	VB	56.0	46.0	12.9	3.7
1.4530	31.2	30.5	10.1	41.3	40.6	VB	56.0	46.0	14.7	5.4



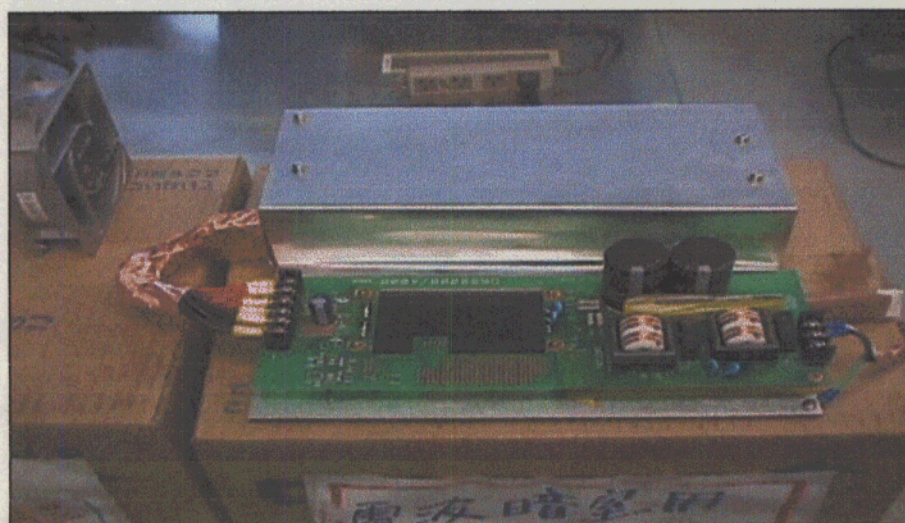
# Conditions

Date 1999/4/9

Test : LINE CONDUCTION

Model Name : DBS200B

○Photographs of Test Set-Up



○Testing circuitry

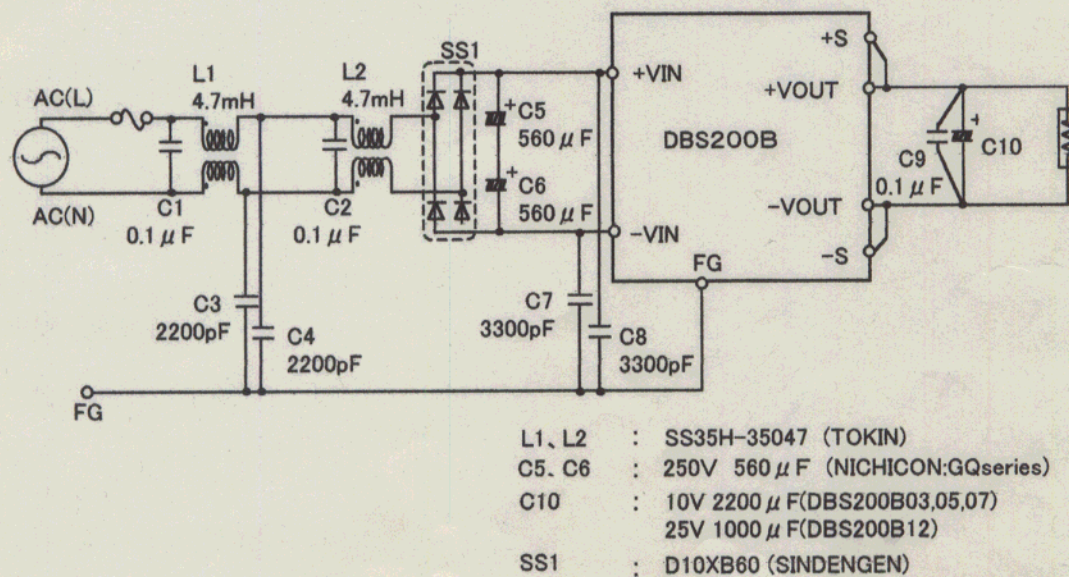


Fig. Testing circuitry